

# AO4443 P-Channel Enhancement Mode Field Effect Transistor



## **General Description**

The AO4443 uses advanced trench technology to provide excellent R<sub>DS(ON)</sub>, and ultra-low low gate charge. This device is suitable for use as a load switch or in PWM applications. *Standard Product AO4443 is Pb-free (meets ROHS & Sony 259 specifications). AO4443L is a Green Product ordering option. AO4443 and AO4443L are electrically identical.* 

## Features

$$\begin{split} V_{DS} (V) &= -40V \\ I_D &= -6.5 \text{ A} (V_{GS} = -10V) \\ R_{DS(ON)} &< 42m\Omega (V_{GS} = -10V) \\ R_{DS(ON)} &< 63m\Omega (V_{GS} = -4.5V) \end{split}$$

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Absolute Maximum	Ratings T <sub>A</sub> =25°C unle	ess otherwise no	oted			
Parameter		Symbol Maximum		Units		
Drain-Source Voltage		V <sub>DS</sub>	-40	V		
Gate-Source Voltage		V <sub>GS</sub>	±20	V		
Continuous Drain	T <sub>A</sub> =25°C		-6.5			
Current <sup>A</sup>	T <sub>A</sub> =70°C	I <sub>D</sub>	-5	A.COM		
Pulsed Drain Current <sup>B</sup>		I <sub>DM</sub>	-20	W.DL		
	T <sub>A</sub> =25°C	D	3.1	10/		
Power Dissipation <sup>A</sup>	T <sub>A</sub> =70°C	-P <sub>D</sub>	2	— W		
Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>STG</sub>	-55 to 150	°C		

Thermal Characteristics						
Parameter Parame		Symbol	Тур	Max	Units	
Maximum Junction-to-Ambient <sup>A</sup>	t ≤ 10s	- R <sub>0JA</sub>	24	40	°C/W	
Maximum Junction-to-Ambient <sup>A</sup>	Steady-State	r <sub>θJA</sub>	54	75	°C/W	
Maximum Junction-to-Lead <sup>C</sup>	Steady-State	$R_{ ext{ heta}JL}$	21	30	°C/W	

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### AO4443

Symbol	Parameter	Conditions		Min	Тур	Max	Units
STATIC F	PARAMETERS						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	I <sub>D</sub> =-250μA, V <sub>GS</sub> =0V		-40			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =-32V, V <sub>GS</sub> =0V				-1	μA
			TJ=55°C			-5	
I <sub>GSS</sub>	Gate-Body leakage current	$V_{DS}$ =0V, $V_{GS}$ =±20V				±100	nA
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS}$ = $V_{GS}$ $I_{D}$ =-250 $\mu$ A		-1	-1.9	-3	V
I <sub>D(ON)</sub>	On state drain current	V <sub>GS</sub> =-10V, V <sub>DS</sub> =-5V		-20			Α
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =-10V, I <sub>D</sub> =-6A			33.3	42	mΩ
			T <sub>J</sub> =125°C		54	68	1115.2
		V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-5A			48	63	mΩ
<b>g</b> <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> =-5V, I <sub>D</sub> =-6A			14		S
$V_{SD}$	Diode Forward Voltage	I <sub>S</sub> =-1A,V <sub>GS</sub> =0V			-0.75	-1	V
ls	Maximum Body-Diode Continuous Cur	Current				-6	Α
	PARAMETERS						
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =-20V, f=1MHz			657		pF
C <sub>oss</sub>	Output Capacitance				143		pF
C <sub>rss</sub>	Reverse Transfer Capacitance				63		pF
$R_{g}$	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz			6.5		Ω
SWITCHI	NG PARAMETERS						
Q <sub>g</sub> (10V)	Total Gate Charge (10V)				14.2		nC
Q <sub>g</sub> (4.5V)	Total Gate Charge (4.5V)		I-=-6A		7.1		nC
Q <sub>gs</sub>	Gate Source Charge	V <sub>GS</sub> =-10V, V <sub>DS</sub> =-20V, 1 <sub>D</sub> =-0A			2.2		nC
$Q_{gd}$	Gate Drain Charge				4.1		nC
t <sub>D(on)</sub>	Turn-On DelayTime	V <sub>GS</sub> =-10V, V <sub>DS</sub> =-20V, R <sub>L</sub> =3.7Ω, R <sub>GEN</sub> =3Ω			7.7		ns
t <sub>r</sub>	Turn-On Rise Time				8		ns
t <sub>D(off)</sub>	Turn-Off DelayTime				26.5		ns
t <sub>f</sub>	Turn-Off Fall Time				11.5		ns
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =-6A, dI/dt=100A/μs	6		21.9		ns
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge	e I <sub>F</sub> =-6A, dI/dt=100A/με	6		14.9		nC

A: The value of  $R_{\theta,JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^{\circ}$ C. The value in any given application depends on the user's specific board design. The current rating is based on the  $\leq$  10s thermal resistance rating. B: Repetitive rating, pulse width limited by junction temperature.

C. The R  $_{\theta JA}$  is the sum of the thermal impedence from junction to lead R  $_{\theta JL}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6,12,14 are obtained using  $80\mu s$  pulses, duty cycle 0.5% max.

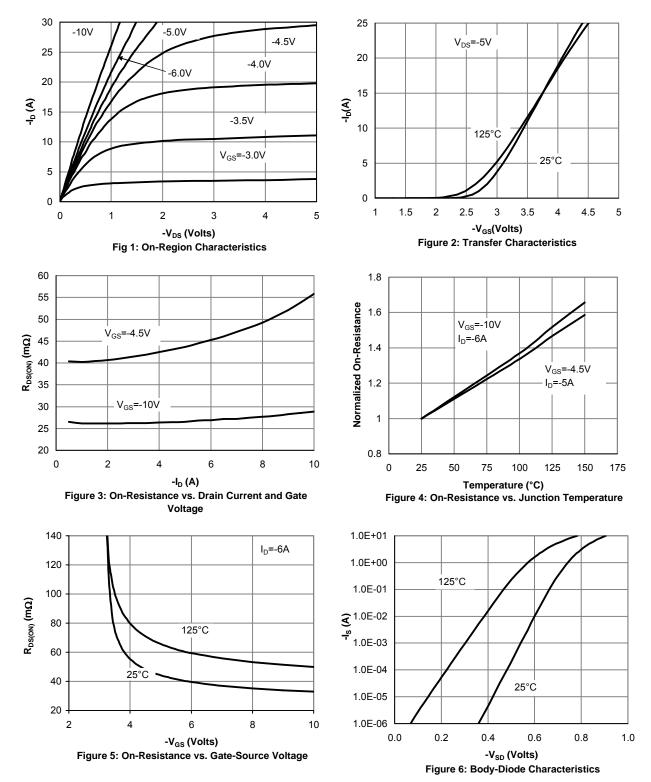
E. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A$ =25°C. The SOA curve provides a single pulse rating.

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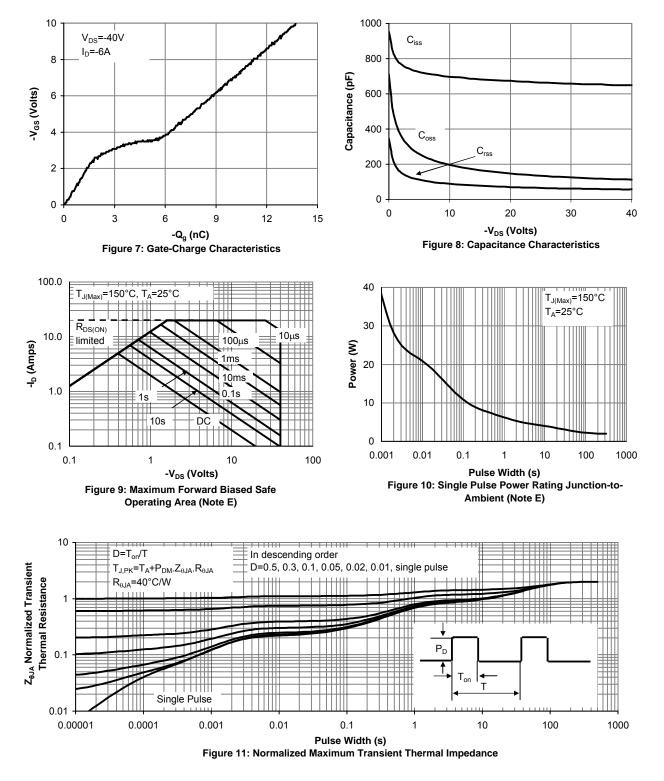
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#### **TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS: P-CHANNEL**





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